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and accurate to serve as a convenient, although approximate, alternative for optical diffraction experiments or numerical simulations of more complicated systems with more than one scattering object in the unit cell and with form factors taken into account.

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# Quantitative Determination of Phases of X-ray Reflection from Three-Beam Diffraction. III. Experiments on Mosaic Crystals

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## Abstract

The method proposed by Chang & Tang [Acta Cryst. (1988), A44, 1065-1072] for quantitative determination of phases of X-ray reflection from three-beam diffraction profiles is applied to an organic crystal of (2R, 3R)-3-acetoxy-5,7-dihydroxy-6-methylflavanone, with a mosaic spread of 0.08°. The expression for the kinematical diffraction intensities is modified according to the kinematical theory of X-ray diffraction in the multibeam regime. Three-beam Umweganregung and Aufhellung diffraction profiles are analyzed. With the help of the modified intensity expression, the crystal symmetry imposed by the space group and the three-beam diffraction geometry, four acentric phases and fourteen centric phases of structure-factor triplets are determined.

# I. Introduction

A theoretical consideration of quantitative phase determination using three-beam multiple diffraction has recently been reported (Chang & Tang, 1988).

Phase determination for diffractions from perfect crystals was also demonstrated subsequently (Tang & Chang, 1988). These two reports are hereafter referred to as papers I and II in the following discussions. In paper I, a general formalism was derived from the dynamical theory of X-ray diffraction. The first-order approximation in the iterative procedure for the fundamental equation of the wavefield was adopted for Umweganregung three-beam diffractions, where the multiple diffracted intensity is greater than the two-beam intensity background. Boundary conditions were considered for plate-like crystals. For Aufhellung three-beam diffractions, where the multiple diffraction intensity is lower than the two-beam background, a second-order approximation was proposed to deduce the expressions for diffraction intensities. In paper II, the experiments for plate-like perfect crystals of GaAs demonstrated the possibility of determining quantitatively the phases of acentric reflections.

In mosaic crystals, lattice perfection is not guaranteed. According to Zachariasen (1945), diffractions

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from mosaic crystals have the magnitude of the parameter A much less than unity. The parameter A is defined as

$$A = r_e \lambda T |F_G| / (V \gamma_0^{1/2} \gamma_G^{1/2})$$
 (1)

where  $r_e$  and  $\lambda$  are the classical radius of the electron and the wavelength of the X-rays used, respectively. V is the volume of the unit cell and  $\gamma_0$  and  $\gamma_G$  are the direction cosines of the incident beam 0 and the diffracted beam G with respect to the inward normal to the crystal surface.  $F_G$  is the structure factor of the G reflection in two-beam cases. In multibeam cases,  $F_G$  stands for the effective structure factor (Juretschke, 1982; Hoier & Marthinsen, 1983). T is the crystal thickness. The smallness of A, *i.e.*  $A \ll 1$ , implies that the coherent dynamical interaction, which carries phase information, is relatively weak. On the other hand, extinction, mainly secondary extinction, affects considerably the kinematical diffraction intensity, while irregular crystal shape imposes complicated boundary conditions for dynamical excitation. All of these introduce difficulties in delineating the dynamical intensity profile from the intensity measurements. It is the purpose of this paper to demonstrate how to combine the three-beam kinematical theory with the dynamical theory so as to separate the contribution of the dynamical diffraction from the kinematical diffraction and consequently to bring out phase information from the weak dynamical diffraction intensities for mosaic crystals.

In the literature, experimental phase determination using X-ray multiple diffraction techniques for mosaic crystals has been reported by Post (1977), Jagodzinski (1980), Chang (1982), Han & Chang (1983), Gong & Post (1983), Shen & Colella (1988), Mo, Hauback & Thorkildsen (1988), Hümmer, Weckert & Bondza (1989) and many others. Detailed references on this subject matter can be found in the review article of Chang (1987).

#### **II.** Theoretical considerations

Consider a three-beam (0, G, L) diffraction in which 0 is the incident diffraction and G and L are the primary and the secondary reflections, respectively. G-L is the coupling between G and L. Recall the recurrent relation, equation (9) of paper I, of the wavefield amplitude  $D_G$  of the G reflection:

$$\mathbf{D}_{G} = A_{G}\chi_{G}\mathbf{K}_{G} \times \mathbf{K}_{G}$$
$$\times \{\mathbf{D}_{0} + A_{L}(\chi_{G-L}/\chi_{G})[\chi_{L}\mathbf{K}_{L} \times (\mathbf{K}_{L} \times \mathbf{D}_{0})$$

$$+\chi_{L-G}\mathbf{K}_{L}\times(\mathbf{K}_{L}\times\mathbf{D}_{G})]\},$$
(2)

$$A_G = 1/[(k^2 - K_G^2) + K_G^2 \chi_0]$$
(3)

$$A_L = 1/[(k^2 - K_L^2) + K_L^2 \chi_0].$$
 (4)

The quantity  $\chi_{G-L}/4\pi$  is the electric susceptibility of

the G-L reflection, which is proportional to the structure factor  $F_{G-L}$ :

$$\chi_{G-L} = \Gamma F_{G-L} = -(\gamma_e \lambda^2 / \pi V) F_{G-L}.$$
 (5)

k and K are the moduli of the wavevectors in vacuum and inside the crystal, respectively.

According to the theorem of reciprocity of optics, it is known that the interchange of the L and G-Lreflections leads to no difference in the wavefield amplitude D. In other words, the two three-beam cases, (0, G, L) and (0, G, G-L), are equivalent (Pinsker, 1977; Chang 1984). However, in the approximation for iteration, the  $D_G$  of (2) violates this theorem of reciprocity because of the presence of the last term in (2). In paper I, we have employed the first-order approximation, where the last term of (2) was dropped, so that the reciprocity is maintained. The relative intensity distribution of the primary reflection G, after the convolution with the crystal mosaic distribution and the instrumental broadening, can be expressed as a function of the azimuthal angle of  $\varphi$  of rotation around the reciprocal-lattice vector g of the G reflection (Chang & Tang, 1988):

$$I'_G = [I_G(3) - I_G(2)] / I_G(2) = I_D + I_K, \qquad (6)$$

where  $I_G(2)$  and  $I_G(3)$  are the diffracted intensities of the G reflection at the two-beam and the threebeam positions, respectively. The dynamical intensity  $I_D$  and the kinematical intensity  $I_K$  are defined as

$$V_D = 2Pa_1 Q[2(\Delta\varphi)\cos\delta - \eta_T\sin\delta]$$
(7)

$$I_K = a_2 \eta_T P^2 / \eta_i \tag{8}$$

where

$$P = |\Gamma|kL_FQ(|F_{G-L}||F_L|/|F_G|)$$
(9)

$$Q = 1/[(\Delta \varphi)^2 + (\eta_T/2)^2]^{1/2}$$
(10)

$$W = kl \sin \alpha \sin \beta_0 \cos \theta_G \tag{11}$$

$$\eta_T = \eta_i + \eta_B + \eta_M \tag{12}$$

$$\eta_i = k^2 |\chi_0| / W.$$
 (13)

 $a_1$  and  $a_2$  are the polarization factors defined as

$$a_1 = (B_0 + B_5 \cos 2\theta_G) p_2 \tag{14}$$

$$a_2 = (B_0^2 + B_3^2 + B_4^2 + B_5^2)p_2 \tag{15}$$

where

$$B_0 = 1 - (l/k)^2 \sin^2 \alpha \sin^2 \beta_0$$
  

$$B_3 = (l/k) \sin \alpha \sin \beta_0 [(l/k) \sin \alpha \cos \beta_0 \sin \theta_G + (l/k) \cos \alpha \cos \theta_G - \sin 2\theta_G]$$
  

$$B_4 = (l/k)^2 (\cos \alpha \cos \theta_G - \sin \alpha \cos \beta_0 \sin \theta_G) \sin \alpha \sin \beta_0$$
  

$$B_5 = \cos 2\theta_G - B_3 B_4 / [(l/k) \sin \alpha \sin \beta_0]^2$$

$$p_2 = 1/(1 + \cos^2 2\theta_G).$$

δ is the phase of the structure-factor triplet  $F_G F_L F_{G-L}$ .  $η_T$  is the total experimental width at half maxima.  $η_i$ ,  $η_B$  and  $η_M$  are the intrinsic diffraction width, the average instrumental broadening and the crystal mosaic spread, respectively.  $\Delta φ$  is the angular deviation from the exact three-beam diffraction position. L is the Lorentz factor defined as k/W. l is the modulus of the reciprocal-lattice vector I of the L reflection.  $θ_G$  and α are the Bragg angle of the G reflection and the angle between the vectors g and l.  $β_0$  is the angle between  $I_{\perp}$  and the plane of incidence, where  $I_{\perp}$  is the vector component of I normal to g. For a plate-like crystal,  $η_i$  can be written as [see equation (35) of paper I]

$$\eta_i = k |L_F|(\gamma_L/\gamma_0)|\chi_0|, \qquad (16)$$

where  $\gamma_0$  and  $\gamma_L$  are the direction cosines. For a crystal of arbitrary shape, we introduce a factor  $C_1$  in  $\eta_i$  to take care of the boundary conditions for wavevectors:

$$C_1 \eta_i = C_1 k |L_F \chi_0|. \tag{17}$$

The approximation for the wavefield amplitudes employs an iteration procedure. This approach is the same as the second-order Bethe approximation (Høier & Marthinsen, 1983; Juretschke, 1982; Hümmer & Billy, 1986) and the Born approximation (Shen, 1986), except that the resonance function  $A_{i}$ of (4) has been introduced to describe the intensity at the peak position. Actually, (6) can also be derived from the Bethe approximation and the Born approximation. On the other hand,  $I_{\kappa}$  given in (8) has exactly the same form as that derived from the kinematical theory for Umweganregung diffraction for a weak primary reflection (Moon & Shull, 1964). Physically, this procedure, valid up to first-order approximation, is not in a strict manner consistent with the 'simultaneous' nature of multiple diffraction. To consider the simultaneous occurrence of diffractions and the kinematical diffractions from mosaic crystals, the kinematical intensity  $I_{\kappa}$  is replaced by the expression derived from the power-transfer equation of the kinematical theory (Moon & Shull, 1964). With a modified coefficient keeping the dimension of  $I_{K}$  the same as that given in (8), the kinematical intensity takes the form

I

$$_{K,T} \simeq (\eta_T/\eta_i) k^2 \Gamma^2 L_F^2 Q^2 R \qquad (18a)$$

$$R = [a_2|F_{G-L}|^2|F_L|^2 - a_3|F_G|^2|F_L|^2 - a_4|F_G|^2|F_{G-L}|^2]/|F_G|^2,$$
(18b)

where the polarization factors  $a_3$  and  $a_4$  are defined as

$$a_{3} = [\cos^{2} 2\theta_{G} + \cos^{2} 2\theta_{L} + (\cos 2\theta_{G-L} - \cos 2\theta_{G} \cos 2\theta_{L})^{2}]p_{2}$$
(19a)  
$$a_{4} = [\cos^{2} 2\theta_{G} + \cos^{2} 2\theta_{G-L}]$$

+ 
$$(\cos 2\theta_L - \cos 2\theta_G \cos 2\theta_{G-L})^2]p_2.$$
 (19b)

 $\theta_L$  and  $\theta_{G-L}$  are the Bragg angles of the L and G-L reflections, respectively. Equation (18*a*) reduces to (8) as  $F_G$  approaches zero. Both (18*a*) and (8) are valid for weak reflections with  $ql_0 < 1$  and  $\mu l_0 < 1$ , where q is the reflectivity defined as

$$q_G = (r_e^2 \lambda^3 / V^2) |F_G|^2 (1 + \cos^2 2\theta) / (2\sin 2\theta_G).$$
(20)

 $\mu$  and  $l_0$  are the linear absorption coefficient and the X-ray path length, respectively.

In practice, the experimental kinematical intensity  $I_{\kappa}$  is different from the theoretical  $I_{\kappa,T}$  given in (18) due to (i) the error of the resonance function  $A_L$  introduced in the iterative procedure, and (ii) the extinctions. For an irregularly shaped crystal, the intensity ratios,  $I_{\kappa}/I_{\kappa,T}$  at  $\Delta \varphi = 0$ , are almost constant for the three-beam diffractions involving approximately the same kinematical intensities, because the effects of the extinctions are almost the same. Under this condition, we could assume that

$$I_K = C_0 I_{K,T} \tag{21}$$

for a set of three-beam diffractions which have similar  $I_{K,T}$  values. If very weak three-beam diffractions are considered (*i.e.*  $ql_0 < 1$ ,  $\mu l_0 < 1$ ), both the primary and secondary extinctions are small. The  $I_{K,T}$  given in (18*a*) is suited for calculating the kinematical intensities.

To determine the scale factor  $C_0$ , we consider the ratio of  $I_{K,T}$  and the experimental intensity of  $I'_G$ , at the peak position,  $\Delta \varphi = 0$ , *i.e.*  $I_P = J'_G (\Delta \varphi = 0)$ , as

$$I_P / I_{K,T}(0) = [I_D(0) + I_K(0)] / I_{K,T}(0)$$
  
= ±4P(0)a<sub>1</sub> sin  $\delta / I_{K,T}(0) + C_0$ , (22)

where the relations (6), (7) and (8) have been used. The plus and minus signs correspond to the *Umweganregung* and the *Aufhellung* diffractions, respectively. If a three-beam diffraction with  $\delta = 0$  or 180°, the  $C_0$  can be determined via the  $I_P/I_{K,T}(0)$ . Thus, the determined  $C_0$  can be used to calculate the  $I_K$  from (21) for the other reflections which have similar  $I_{K,T}$  values.

From (22), we notice that if  $\delta > 0$  and  $a_1 > 0$ ,  $I_P/I_{K,T}(0) < C_0$  for Umweg and  $I_P/I_{K,T}(0) > C_0$  for Aufhellung. If  $\delta < 0$  and  $a_1 > 0$ , the situations are reversed for Umweg and Aufhellung.

It should be noted that the  $\Delta \varphi$  in the first term of (7) involves the sign of  $L_F$ , which is defined as (Chang & Tang, 1988)

$$S(L_F) = S \pm S_{GL}, \tag{23}$$

where  $S_{\pm}$  is positive for the 'IN' position  $\varphi_{+}$  at which the reciprocal-lattice point *L* is entering the Ewald sphere;  $S_{\pm}$  is negative for the 'OUT' position  $\varphi_{-}$  at which the reciprocal-lattice point *L* is leaving the Ewald sphere.  $S_{GL}$  is the sign of  $l^2 - 1 \cdot g$  (Shen, 1986). That is, the sign of  $\cos \delta$  to be determined via (7) depends on  $S(L_F)$ , while the sign of sin  $\delta$  is independent of  $S(L_F)$ .

With the determined  $C_0$  factor, the measured  $\eta_T$ , the calculated  $\eta_i$ ,  $a_2$ ,  $a_3$ ,  $a_4$ , and the structure-factor amplitudes deduced from two-beam intensity measurements, the kinematical diffraction profile  $I_K(\Delta\varphi)$  can be calculated as

$$I_{K}(\Delta \varphi) = C_{A} \mathscr{L}(\Delta \varphi) \tag{24}$$

where

$$C_{A} = C_{0} \Gamma^{2} k^{2} L_{F}^{2} (\eta_{T} / \eta_{i}) R \qquad (25)$$

$$\mathscr{L}(\Delta \varphi) = Q^2. \tag{26}$$

 $\mathscr{L}$  is a Lorentzian. The azimuthal position  $\varphi_+$  or  $\varphi_$ at the exact three-beam point,  $\Delta \varphi = 0$ , is the center of the Lorentzian.  $\varphi_{\pm}$  can be calculated according to the diffraction geometry (Cole, Chambers & Duun, 1962; Chang & Tang, 1988). The dynamical diffraction profile  $I_D(\Delta \varphi)$  is then equal to  $I_D(\Delta \varphi) =$  $I'_G(\Delta \varphi) - I_K(\Delta \varphi)$ . The phase angle  $\delta$  for  $a_1 L_F > 0$ can be determined according to the relations (Chang & Tang, 1988)

$$\cos \delta - \sin \delta = I_{+}/(2Pa_{1}QW)|_{\Delta \varphi = \eta_{T}/2} \quad (27a)$$

$$-\cos \delta - \sin \delta = I_{-}/(2Pa_{1}QW)|_{\Delta\varphi = \eta_{T}/2}, \quad (27b)$$

where

$$I_{\pm} = I_D(\Delta \varphi = \pm \eta_T/2). \tag{28}$$

If  $a_1L_F < 0$ , to the  $\delta$  determined from (27) should be added -90°. The details about adjusting the value of  $\delta$  according to the experimental and geometrical parameters are given in §§ IV and V. For later discussion, the phase angle calculated from (27) is denoted as the nominal phase  $\delta^*$ .

#### **III.** Experimental

An organic crystal of (2R, 3R)-3-acetoxy-5,7-dihydroxy-6-methylflavanone, C<sub>18</sub>H<sub>16</sub>O<sub>6</sub> (Fang, Chang & Cheng, 1987), was used for the experiments. The crystal is about 0.4 mm in diameter. The crystal belongs to the monoclinic system, space group *I*121, with four (Z=4) molecules in the unit cell. The cell dimensions are a = 14.4881, b = 8.0342, c =14.3406 Å and  $\beta = 110.76^{\circ}$  (Cheng, Cheng, Chang & Wang, 1989). The mosaic spread of the crystal measured from rocking curves is about 0.08°. The two-beam Bragg diffraction intensities were collected as usual by using an Enraf-Nonius CAD-4 diffractometer with Mo  $K\alpha$  radiation. The moduli of the structure factors were deduced from the measured intensities. Those used for calculating  $I_{K,T}$  are listed in Table 1. The crystal was then mounted on a Huber 400 semi-automatic goniometer to perform multiple diffraction experiments. An Elliott GX-21 rotatinganode X-ray generator was used. The details of the

Table 1. Structure factors of C<sub>18</sub>H<sub>16</sub>O<sub>6</sub> for Mo Kα radiation

hkl	F	hkl	F
000	680	202	62
002	35	204	61
004	65	204	52
013	117	211	35
015	30	21ī	35
ī01	96	213	53
101	96	222	80
101	4	303	49
103	27	303	103
103	265	312	102
105	5	312	102
112	138	312	102
114	88	402	18
Ĩ23	47	411	29
200	14	514	36

experimental set-up can be found in paper II. The beam divergence is about  $0.03^{\circ}$ . Fig. 1 shows the 101 multiple diffraction pattern obtained with Cu Ka  $(\lambda = 1.541838 \text{ \AA})$  radiation. 101 is the primary G reflection. Multiple-diffraction Umweg peaks are indexed with the Miller indices of the secondary reflections L. Several indices sharing the same peak indicate the overlapping of several reflections including high-order N-beam (N > 3) diffractions. (Because of the relatively crowded peak distribution, not all of the peaks are labelled with their secondary reflections L in Fig. 1.) The origin,  $\varphi = 0$ , of the azimuthal rotation angle  $\varphi$  corresponds to the position at which the [010] direction coincides with the plane of incidence of the 101 reflection. The arrow shows the running direction of the paper chart. Fig. 2 shows part of the 303 multiple diffraction pattern for Cu  $K\alpha$  radiation. All the multiple diffractions are of *Aufhellung* type. The uneven two-beam 303, as well as 101, reflection background is due to the boundary effect of the irregularly shaped crystal. The symmetry about  $\varphi = 0$ of the two-beam intensity distribution visible in Figs. 1 and 2 indicates that the crystal shape is somewhat symmetric about the [010] direction.



Fig. 1. Multiple diffraction (*Umweg*) pattern of 101  $C_{18}H_{16}O_6$  for Cu K $\alpha$  radiation ( $\lambda = 1.541838$  Å).

Step scan,  $I'_G$  versus  $\Delta\varphi$ , was carried out for each of the unoverlapped three-beam diffractions for 101 and 303  $\varphi$  scans. The error in counting statistics for intensity measurements was kept less than 1%. Some of the step-scanned profiles  $I'_G(\Delta\varphi)$  are shown, as examples, in Figs. 4 and 5 for Umweg and Aufhellung, respectively. The peak positions  $\varphi_{\pm}$ , defined as  $\Delta\varphi =$ 0, for each three-beam diffraction are determined according to equation (25) of paper I and the relation  $\varphi_{\pm} = \varphi_0 \pm \beta_0$ , where  $\varphi_0$  is the initial azimuthal position of the reciprocal-lattice point L with respect to the plane of incidence of the primary G reflection. The peak intensities  $I_P = I'_G(\Delta\varphi = 0)$  were recorded and the peak widths at half maxima were measured.

# IV. Data analysis and phase determination

The scale factor  $C_0$ , as discussed in § II, can be determined from the  $I_P/I_{K,T}(0)$  values of weak threebeam centrosymmetric diffractions via (22). For space group I121, hkl with k = 0 are centric reflections. The corresponding three-beam cases,  $h0l/1 - h_{0,1} - l$  and  $h0l/3 - h_0 (3 - l)$  are also centric, where the indices before and after the slashes represent L/G - L. Table 2 lists the  $I_{K,T}(0)$  and  $I_P$  values for the weakest reflections of the 101 and 303 scans. The two-beam intensities of 101 and 303 calculated according to (20) are also given. The  $I_G^{(3)} - I_G^{(2)}$  values, which are proportional to  $I_{K,T}(0)I_G^{(2)}$  are about  $3 \times 10^{-8}$  for the reflections of the 101 scan and  $4 \times 10^{-6}$  for the 303 scan. Since  $I_G^{(3)} - I_G^{(2)}$  are very weak and  $ql_0 < 1$  and  $\mu l_0 \sim 10$  $(cm^{-1}) \times 0.04 (cm) = 0.40$ , it is justifiable to employ (18a) for the calculation of  $I_{K,T}(0)$  for the reflections listed in Table 2. From Table 2 for the 101 scan, 303,  $\overline{2}04$ ,  $\overline{3}12$  and  $\overline{1}23$  reflections have  $I_{K,T}(0)$  values ranging from 0.07 to 0.09. The centric three-beam reflections  $30\overline{3}$  and  $\overline{2}04$  were used to determine the scale factor  $C_0$ . As shown in Fig. (3*a*), the averaged  $C_0$  is 6.87 with 8.28 and 5.60 as the upper and lower bounds, respectively. Since  $30\overline{3}$  and  $\overline{2}04$  are symmetryrelated equivalent reflections, *i.e.*  $30\overline{3}/\overline{2}04$  with



Fig. 2. Multiple diffraction (Aufhellung) pattern of 303  $C_{18}H_{16}O_6$ for Cu K $\alpha$  radiation.

Table 2. The  $I_{K,T}(0)$  and  $I_P$  values for weak three-beam diffractions

L	$I_{\kappa,\tau}(0)$	$I_P$
(a) $G = 101 [I_G^{(2)} \sim q l_0 \sim 4]$	< 10 <sup>-7</sup> ]	
303	0.020	0.553
204	0.075	0.436
312	0.072	0.480
123	0.092	0.115
(b) $G = 303 [I_G^{(2)} \sim 8 \times 10^{-6}]$	]	
514	0.0022	0.021
105	0.0033	0.019
202	0.0052	0.024
312	0.0061	0.005

respect to  $\overline{2}04/30\overline{3}$ , they are supposed to have the same  $I_P/I_{K,T}(0)$  values. However, owing to the experimental errors, for example, the crystal boundary effects, the possible inhomogeneous intensity distribution of the incident beam and the crystal misalignment,  $30\overline{3}$  and  $\overline{2}04$  have slightly different values in  $I_P/I_{K,T}(0)$ . This difference is considered to be the principal error in  $C_0$ . The error in counting statistics is indicated as an error bar in Fig. 3. The



Fig. 3. Scaling for (a) 101 Umweg and (b) 303 Aufhellung.

mechanical backlash of the  $\varphi$  scan was checked to be very small. It has very little effect on the peak positions. The  $C_0$  value obtained was then used to calculate the  $I_K$  for  $\overline{3}12$  and  $\overline{1}23$  reflections.

For the 303 scan, the centric three-beam reflections 105 and 20 $\overline{2}$  were used for the scaling (see Fig. 3b). The scale factor  $C_0$  is equal to 5.19 with 6.15 and 4.40 as the upper and lower bounds. With this  $C_0$  value, the  $I_K$  of 5 $\overline{14}$  and 3 $\overline{12}$  reflections are calculated via (24).

The scaling shown in Figs. 3(a) and (b) also provides information about the enantiomorph (for example, see Ladd & Palmer, 1980) for acentric reflections. For *Umweg* (Fig. 3a),  $\overline{123}/2\overline{22}$  has  $I_P/I_{K,T}(0)$  values less than the average  $C_0$  value. This implies that the sign of sin  $\delta^*$  is positive. For *Aufhellung* (Fig. 3b), the  $I_P/I_{K,T}(0)$  of  $5\overline{14}/\overline{211}$  is greater than while that of  $3\overline{12}/015$  is less than  $C_0$ , *i.e.* the sign  $S(\sin \delta^*) > 0$  for  $5\overline{14}/\overline{211}$  and  $S(\sin \delta^*) < 0$  for  $3\overline{12}/015$ .

The kinematical diffraction intensities  $I_K(\Delta\varphi)$  are constructed according to (24) for acentric reflections. Figs. 4 and 5 show the constructed  $I_K$ , the experimental profiles  $I'_G$  and the dynamical profiles  $I_D(=$  $I'_G - I_K)$  for the 101 and 303 scans, respectively. The running direction of the paper chart is also indicated. The determined  $\delta$ 's from  $I_D$  via (27) are listed in Table 3 as  $\delta^*$ 's, together with the signs,  $S_{\pm}$ ,  $S_{GL}$ ,  $S_L(C)$ ,  $S(\cos \delta)$ ,  $S(\sin \delta)$  and  $s(a_1)$ , where

$$S(\cos \delta) = S(a_1)S(L_F)S_L(C)$$

$$= S(a_1)S_{\pm}S_{GL}S_L(C) \tag{29}$$

$$S(\sin \delta) = S(a_1)S(\sin \delta^*).$$
(30)

 $S(a_1)$  is the sign of the polarization factor  $a_1$ .  $S_L(C)$  is the sign defined from the asymmetry of the tails of the diffraction intensity profiles (Chang, 1982). The relation (30) is established based on (7) and (22). The  $\delta^*$ 's are the nominal phases which need to be

0.01





Fig. 4. Intensity profiles of  $I'_G$ ,  $I_K$  and  $I_D$  for the 101 Umweg: (a)  $\overline{1}23/2\overline{22}$  and (b)  $\overline{3}12/4\overline{11}$  (the peak  $\overline{1}14$  is nearby).

Fig. 5. Intensity profiles of  $I'_G$ ,  $I_K$  and  $I_D$  for the 303 Aufhellung: (a)  $5\overline{14}/\overline{211}$  (the peak 206 is nearby) and (b)  $3\overline{12}/015$ .

L/G-L	$S(a_1)$	$S_{\pm}$	$S_{GL}$	$S_L(C)$	$S(\cos \delta)$	δ*(°)	$S(\sin \delta)$	$\delta_E(^\circ)$	$\delta_T(^\circ)$
(a) 101 Umwe	g (G = 101)								
123/222	+	+	+	+	+	26	+	26	23
312/411	+	+	+	-	-	181	-	181	171
101/002	+	+	+	+	+			0	0
103/004	+	+	+	+	+			0	0
002/101	+	+	+	+	+			0	0
004/103	+	+	+	+	+			0	0
303/204	+	-	+	-	-			180	180
204/303	+	-	+	-	-			180	180
(b) 303 Aufhe	llung (G=303)								
514/211	+	+	+	-	-	136	+	136	132
312/015	+	+	+	-	-	-79	-	-169	-145
200/103	+	-	-	+	+				0
105/202	+	-	+	+	-				180
<b>ī</b> 01/402	+	-	+	+	-				180
204/101	+	-	+	-	+				0
402/101	+	+	+	-	-				180
101/204	+	+	+	+	+				0
202/105	+	+	÷	-	-				180
103/200	+	+	-	-	+				0

Table 3. Exper	rimentally determined	phases for	$C_{18}H_{16}O_{6}$	$(\lambda = 1.541838 \text{ Å})$
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corrected according to the signs of  $S(\cos \delta)$  and  $S(\sin \delta)$ . The corrected phases are listed as  $\delta_E$ . The theoretical phases  $\delta_T$ , calculated from the known atomic positions of the crystal, are also given.

The phases  $\delta$  of those centric diffractions are also determined according to the signs of  $\cos \delta$ ,  $S(\cos \delta)$ .

### V. Discussion and concluding remarks

The main error in the determination of acentric phases comes from the errors in determining the  $C_0$  value. From (21), the error  $\Delta C_0/C_0$  is proportional to the sum of  $\sum \Delta I_{K,T} / I_{K,T}$  and  $\sum \Delta I_P / I_P$ . The former is due mainly to the theoretical approximation and the extinctions and the latter results from the inaccuracy in the intensity measurements. Because of the crystal cell dimensions and the wavelength used, overlapping of multiple diffraction profiles is unavoidable. This overlapping certainly affects the intensity profiles and their positions. On the other hand, the irregular crystal boundaries cause complex dynamical excitation and the primary extinction which not only change the intensity distribution but also shift the peak position away from  $\varphi_{\pm}$ . Since the errors associated with  $\Delta I_{KT}$ and  $\Delta I_P$  are not directly attainable, we can estimate the error  $\Delta C_0/C_0$  only from the intensity variation of the two symmetry-related equivalent reflections and the counting statistics (see Fig. 3). The estimated  $\Delta C_0/C_0$  is about  $\pm 20\%$  for the Umweg and  $\pm 18\%$ for the Aufhellung. The corresponding errors in the nominal phase  $\delta^*$  determined via (27) are within  $\pm 5^\circ$ for Lorentzian and Gaussian kinematical profiles for 123/222, 514/211 and 312/015 (Table 4). The errors in  $\delta^*$  for  $\frac{312}{411}$  are about  $\pm 25^\circ$ . This is because the  $I_P/I_{K,T}(0)$  value is so close to the  $C_0$  value. Slight variation across  $C_0$  may change the sign of  $\delta^*$ , which will certainly cause a large error in  $\delta^*$ . From Fig. 3(*a*),  $\overline{3}12$  lies in between 303 and  $\overline{2}04$ . This indicates that  $\overline{3}12$  is practically a centric reflection.

Since we dealt with the weak diffractions from mosaic crystals, the effects of the phases on the intensity profiles are not obvious. To doubly check the determined phases, we use the asymmetry of the tails of the profile  $I'_G$  to determine the sign of  $\cos \delta$ via (29) (Chang, 1982; Chang & Valladares, 1985). The experimental phase  $\delta_E$  is then adjusted according to  $S(\cos \delta)$  and  $S(\sin \delta)$ . For example, in Fig. 5(b), the nominal phase  $\delta^*$  determined from the  $I_D$  curve is  $-79^\circ$ . This contradicts the fact that  $S(\cos \delta) < 0$ and  $S(\sin \delta) < 0$ , *i.e.*  $\delta$  must be in the third quadrant. The experimental phase  $\delta_E$  is therefore corrected to  $-79-90^\circ = -169^\circ$ . From Table 3, the maximum difference between  $\delta_E$  and  $\delta_T$  is about 25°.

It should be noted that the nominal phase  $\delta^*$  is determined directly from the line profile  $I'_G$  obtained experimentally. The factors such as  $S(a_1)$ ,  $S_{\pm}$ ,  $S_{GL}$ ,  $S(\cos \delta)$  and  $S(\sin \delta)$  have not been considered in calculating  $\delta^*$ . The final experimental phase should therefore follow the relations given in (29) and (30) and should be adjusted to fit in the correct quadrant.

In deriving (18), we have adopted the expression for the diffracted intensity from the kinematical theory (Moon & Shull, 1964). Although the expression was originally derived for low extinction and weak reflections, its form, satisfying the theorem of reciprocity, seems to be quite general. A similar expression for the kinematical intensity has also been derived from the Takagi-Taupin equation for a parallelepiped crystal (Thorkildsen, 1987). The difference between the two is in the consideration of the crystal boundaries. In the present case, the extincTable 4. The determined nominal phases  $\delta^*$  and the errors  $\pm \Delta \delta^*$  corresponding to the lower and upper bounds of  $C_0$ 

	$\delta^*(+\Delta\delta^*,-\Delta$	δ*)(°)
L	Lorentzian	Gaussian
(a) $G = 101$		
123	26(+3,-3)	40 (+3, -3)
312	181 (+22, -25)	159 (+26, -21)
(b) $G = 303$		
514	136(+2,-1)	138 (+2, -2)
312	-79 (+5, -4)	-83 (+4, -3)

tion effects on the diffracted intensity are relatively small because the reflections involved are very weak. However, the crystal boundary seems to affect the intensity considerably. This can be seen directly from the comparison of the intensity backgrounds of the 101 and 303  $\varphi$  scans.

The scaling factor  $C_0$ , defined in (21) to match the experimental and the theoretical kinematical intensities, has values greater than unity. The deviation of  $C_0$  from unity is attributed to the theoretical approximation, extinctions and crystal boundary effects. Since extinction is small and (18) is valid for the present situation, the crystal boundary becomes the dominant effect. In paper II, plate-like crystals were used for the multiple-diffraction experiments. In that case, the crystal boundary is well defined. The corresponding peak intensity is proportional to the ratio of the direction cosines,  $\gamma_0/\gamma_L$ .  $C_0$  is about 0.91 for Cu  $K\alpha_1$  (see paper II). When  $\gamma_L$  approaches zero, the peak intensity  $I_P$  increases. It is therefore not surprising to have  $C_0$  greater than unity when an irregularly shaped crystal is used.

The negative dynamical intensities  $I_D$ , shown in Figs. 4 and 5, represent the intensities which are taken away from the kinematical intensities  $I_K$  of the primary reflections and transferred to the secondary reflections via dynamical interaction. For  $I_D > 0$ , the primary reflection gains intensity from the secondary reflection. This can be understood from the theoretical derivation and the calculated intensities given in paper I.

In paper I, we had adopted the term 'kinematical' for the intensity  $I_K$  which is independent of the reflection phases. This intensity is considered as the incoherent intensity. According to Kato (1980), by no means does the incoherent intensity result solely from the incoherent waves. Instead, coherent waves can also contribute to the incoherent intensity. Therefore, the 'kinematical' intensity  $I_K$  is attributed to both coherent and incoherent waves inside the crystal. Moreover, it is worth noting that, in the case of *Umweganregung*, the  $I_K$  derived from the fundamental equation of the wavefield, (2), has the same form as that from the kinematical theory. The strength of the dynamical interaction which conveys the phase information in the multiply diffracted intensity distribution resulting from the coherent waves in the crystal depends, as stated in (1), on the parameter A. In order to increase the dynamical effect, strong reflections, long wavelengths and large crystals are ideal for the experiments. However, in practice, for irregularly shaped small crystals, compromised experimental conditions should be considered to reduce to minima the absorption, extinction and crystal boundary effects.

In conclusion, we have demonstrated that by modifying the expression for the kinematical intensity  $I_K$  with that derived from the kinematical theory and with the aid of crystal symmetry imposed by the space group, quantitative phase determination from weak three-beam diffraction can be achieved for mosaic crystals, with relatively large errors compared with that for perfect crystals. Further investigation is suggested to study the effects of crystal boundary on the intensity profiles of three-beam diffraction from noncentrosymmetric crystals so that improved precision in determining the phases is attainable.

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